

In response to the Office Action dated March 4, 2003 kindly amend the  
subject application as follows:

b.) Amendments to the Specification:

Please amend the specification on page 80, lines 7-19 to read as follows:

- - Examples of the mechanical impact application apparatus may include:

mechanical pulverizers, such as ~~Krypron System~~ "KRYOPRON SYSTEM" (made by  
Kawasaki Jukogyo K.K.) and "~~Turbomill~~" "TURBOMILL" (made by Turbo Kogyo K.K.),  
and mechanical impacting devices, such as "~~Mechanofusion System~~"  
"MECHANOFUSION SYSTEM" (made by Nara Kikai Seisakusho K.K.) and  
"~~Hybridization System~~" "HYBRIDIZATION SYSTEM" (made by Nara Kikai Seisakusho  
K.K.) wherein toner particles are pressed against an inner wall of a casing under action of a  
centrifugal force exerted by blades stirring at high speeds, thereby applying mechanical  
impact forces including compression and abrasion forces to the toner particles. - -

Please amend the specification on page 108, line 6 to page 109, line 11 to  
read as follows:

- - The particle size distributions and average particle sizes may be measured by using, e.g.,  
Coulter Counter Model TA-II or Coulter ~~Multicizer~~ MULTISIZER (respectively available  
from Coulter Electronics, Inc.). Herein, these values are determined based on values  
measured by using Coulter ~~Multicizer~~ MULTISIZER connected to an interface (made by  
Nikkaki K.K.) and a personal computer ("PC9801", made by NEC K.K.) for providing a  
number-basis distribution and a volume-basis distribution in the following manner. A 1%-

aqueous solution is prepared as an electrolytic solution by using a reagent-grade sodium chloride (it is also possible to use ISOTON R-II (available from Coulter Scientific Japan K.K.)). For the measurement, 0.1 to 5 ml of a surfactant, preferably a solution of an alkylbenzenesulfonic acid salt, is added to a dispersant into 100 to 150 ml of the electrolytic solution, and 2-20 mg of a sample toner is added thereto. The resultant dispersion of the sample in the electrolytic solution is subjected to a dispersion treatment for ca. 1-3 minutes by means of an ultrasonic disperser, and then subjected to measurement of particle size distribution in the range of 2.00 - 40.30  $\mu\text{m}$  divided into 13 channels by using the above-mentioned Coulter counter with a 100  $\mu\text{m}$ - aperture to obtain a volume-basis distribution and a number-basis distribution. From the volume-basis distribution, a weight-average particle size ( $D_4$ ) and a volume-average particle size ( $D_v$ ) are calculated by using a central value as a representative value channel. From the number-basis distribution, a number-average particle size ( $D_1$ ) and a number-basis variation coefficient ( $S_1$ ) is calculated. - -

Please amend the specification on page 119, lines 9-12 to read as follows:

- - The cells may preferably have concavities providing an average cell diameter corresponding to spheres of 5 - 300  $\mu\text{m}$  and also a void areal percentage at the surface of 15 - 90 %.- -

Please amend the specification on page 130, line 23 to page 131, line 4 to read as follows:

- - The AC voltage may preferably have a peak voltage of ~~below~~ below  $2 \times V_{th}$  ( $V_{th}$ : discharge initiation voltage at the time of DC voltage application). If this condition is not satisfied, the potential on the image-bearing member is liable to be unstable. The AC voltage applied in superposition with a DC voltage may more preferably have a peak

CV voltage below  $V_{th}$  so as to charge the image-bearing member without being substantially accompanied with a discharge phenomenon. - -

Please amend the specification on page 133, line 26 to page 134, lines 5 to read as follows:

CB - - The classification method and apparatus used for production of magnetic particles are not particularly limited. In order to obtain a desired particle size efficiently, it is preferred use a sloped inertia classifier such as ~~"Elbow Jet"~~ "ELBOW JET", a centrifugal ~~separator~~ separator, such as ~~"Dispersion Separator"~~ "DISPERSION SEPARATOR" or "Turboplex" "TURBOPLEX", or sieving. - -

Please amend the specification on page 148, lines 6 - 10 to read as follows:

CB - - During the formation of the photoconductor layer 203, the electroconductive support ~~21~~ 201 may be held at an optimally set temperature, preferably 200 - 350 °C, more preferably 230 - 330 °C, further preferably 250 - 310 °C. - -

Please amend the specification on page 148, line 26 to page 149, line 10 to read as follows:

CB - - The surface layer ~~24~~ 204 may comprise any non-single crystal material. For example, the surface layer may comprise: amorphous silicon containing hydrogen (H) and/or halogen (X) and further carbon (C) (denoted by "a-SiC:H,X"), amorphous silicon containing hydrogen (H) and/or halogen (X) and further oxygen (O) (denoted by "a-SiO:H,X"), amorphous silicon containing hydrogen (H) and/or halogen (X) and further nitrogen (N) (denoted by "a-SiN:H,X"), and amorphous silicon containing hydrogen (H) and/or halogen (X) and further at least one of carbon (C), oxygen (O) and nitrogen (N) (denoted by "a-SiCON:H,X"). - -

Please amend the specification on page 160, line 26 to page 161, line 12, to

read as follows:

- - The surface roughness (Ra) values described herein are based on values measured as center line average roughness values by using a surface roughness meter (~~"Surfcorder SE-30H"~~ "SURFCORDER SE-30H", available from K.K. Kosaka Kenkyusho) according to JIS B-0601. More specifically, based on a surface roughness curve obtained for a sample surface, a length of  $\lambda$  is taken along a center line of the roughness curve. The roughness curve is represented by a function  $Y = f(x)$  while setting the X-axis on the center line and a roughness scale (y) on the Y-axis along the length x portion. A center line-average roughness Ra of the roughness curve is determined by the following formula:- -